

Form PTO 1449
(Modified)U.S. DEPARTMENT OF COMMERCE
PATENT AND TRADEMARK OFFICE

ATTY DOCKET NO.

248760US0RDCONT

SERIAL NO.

New Continuation of

~~10/188,744~~ 10/193,297

LIST OF REFERENCES CITED BY APPLICANT

APPLICANT

Yasuo OHBA

FILING DATE

Herewith

2-9-04

GROUP

2822

U.S. PATENT DOCUMENTS

EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUB CLASS	FILING DATE IF APPROPRIATE
IMS	AA	4,792,958	12/20/88	OHBA, et al.	372	45.01	
	AB	4,809,287	02/28/89	OHBA, et al.	372	45.01	
	AC	4,835,117	05/30/89	OHBA, et al.	438	40	
	AD	4,949,349	08/14/90	OHBA, et al.	372	45.01	
	AE	4,910,743	03/20/90	OHBA, et al.	372	45.01	
	AF	4,928,285	05/22/90	KUSHIBE, et al.	372	45.01	
	AG	4,893,313	01/09/90	HATAKOSHI, et al.	372	46.01	
	AH	5,076,800	12/31/91	MILNES, et al.	439	394	
	AI	5,036,521	07/30/91	HATAKOSHI, et al.	372	45.01	
	AJ	5,168,077	12/01/92	ASHIZAWA, et al.	117	102	
	AK	5,042,043	08/20/91	HATANO, et al.	372	45.01	
	AL	5,005,057	04/02/91	IZUMIYA, et al.	257	13	
	AM	5,079,184	01/07/92	HATANO, et al.	117	102	
IMS	AN	5,103,271	04/07/92	IZUMIYA, et al.	257	94	

FOREIGN PATENT DOCUMENTS

		DOCUMENT NUMBER	DATE	COUNTRY	TRANSLATION	
					YES	NO
IMS	AO	2000-31588	01/28/00	JAPAN		X
	AP					
	AQ					
	AR					
	AS					
	AT					
	AU					
	AV					

OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, etc.)

AW	Y. OHBA, et al., Japanese Journal of Applied Physics, Vol. 37 Part 2, No. 8A, pp. L 905 - L 906, "FABRICATION AND CHARACTERIZATION OF AlGaIn/GaN DOUBLE HETEROLASER STRUCTURES ON SAPPHIRE SUBSTRATES USING SINGLE CRYSTALLINE AlN BUFFER LAYERS," August 1, 1998.
AX	
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<input type="checkbox"/> Additional References sheet(s) attached	

Examiner

Date Considered

7/24/06

*Examiner's Initial if reference is considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

Form PTO 1449 (Modified)		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY DOCKET NO. 248760USORDCONT		SERIAL NO. New Continuation of 10/188,744 10/193,297	
LIST OF REFERENCES CITED BY APPLICANT				APPLICANT Yasuo OHBA		GROUP 2822	
				FILING DATE Herewith 2-9-04			
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EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUB CLASS	FILING DATE IF APPROPRIATE
IWO	AA	5,228,044	07/13/93	OHBA	372	45.01	/
	AB	5,235,194	08/10/93	IZUMIYA, et al.	257	13	
	AC	5,273,933	12/28/93	HATANO, et al.	117	09	
	AD	5,317,167	05/31/94	IZUMIYA, et al.	257	13	
	AE	5,432,808	07/11/95	HATANO, et al.	372	45.01	
	AF	5,617,438	04/01/97	HATANO, et al.	372	45.01	
	AG	5,740,192	04/14/98	HATANO, et al.	372	45.01	
	AH	5,998,810	12/07/99	HATANO, et al.	257	102	
	AI	6,242,764	06/05/01	Y. OHBA, et al.	257	190	
	AJ	5,990,495	11/23/99	Y. OHBA	257	94	
	AK	5,656,832	06/01/99	Y. OHBA, et al.	257	190	
	AL	5,909,040	06/01/99	Y. OHBA, et al.	257	190	
	AM	5,929,466	07/27/99	Y. OHBA, et al.	257	103	
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		DOCUMENT NUMBER	DATE	COUNTRY	TRANSLATION		
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Examiner <i>John M. Seward</i>					<input type="checkbox"/> Additional References sheet(s) attached Date Considered 7/24/00		
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LIST OF REFERENCES CITED BY APPLICANT				APPLICANT Yasuo OHBA		GROUP 2822	
				FILING DATE Herewith 2-9-04			
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EXAMINER INITIAL	DOCUMENT NUMBER	DATE	NAME	CLASS	SUB CLASS	FILING DATE IF APPROPRIATE	
ims	AA	5,146,465	09/92	KHAN, et al.	372	4501	/
	AB	6,259,122	07/01	OTA, et al.	257	101	
	AC	5,875,052	02/99	SHMAGIN, et al.	359	244	
	AD	6,306,672 B1	10/01	KIM	438	20	
	AE	6,046,464	04/00	SCHETZINA	257	96	
	AF	6,440,823 B1	08/02	VAUDO, et al.	438	498	
	AG	5,929,467	07/99	KAWAI, et al.	257	192	
	AH	5,923,058	07/99	AGARWAL, et al.	257	198	
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	DOCUMENT NUMBER	DATE	COUNTRY	TRANSLATION YES NO			
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